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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	38
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 13x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-UFQFN Exposed Pad
Supplier Device Package	48-UFQFPN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f091ccu7tr

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1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F091xB/xC microcontrollers.

This document should be read in conjunction with the STM32F0xxxx reference manual (RM0091). The reference manual is available from the STMicroelectronics website www.st.com.

For information on the ARM® Cortex®-M0 core, please refer to the Cortex®-M0 Technical Reference Manual, available from the www.arm.com website.



Table 2. STM32F091xB/xC family device features and peripheral counts

Peripheral		STM32F091Cx		STM32F091Rx		STM32F091Vx	
Flash memory (Kbyte)		128	256	128	256	128	256
SRAM (Kbyte)		32					
Timers	Advanced control	1 (16-bit)					
	General purpose	5 (16-bit) 1 (32-bit)					
	Basic	2 (16-bit)					
Comm. interfaces	SPI [I ² S] ⁽¹⁾	2 [2]					
	I ² C	2					
	USART	6	8				
	CAN	1					
	CEC	1					
12-bit ADC (number of channels)		1 (10 ext. + 3 int.)		1 (16 ext. + 3 int.)			
12-bit DAC (number of channels)		1 (2)					
Analog comparator		2					
GPIOs		38		52		88	
Capacitive sensing channels		17		18		24	
Max. CPU frequency		48 MHz					
Operating voltage		2.0 to 3.6 V					
Operating temperature		Ambient operating temperature: -40°C to 85°C / -40°C to 105°C Junction temperature: -40°C to 105°C / -40°C to 125°C					
Packages		LQFP48 UFQFPN48		LQFP64 UFBGA64 WLCSP64		LQFP100 UFBGA100	

1. The SPI interface can be used either in SPI mode or in I²S audio mode.

3 Functional overview

Figure 1 shows the general block diagram of the STM32F091xB/xC devices.

3.1 ARM[®]-Cortex[®]-M0 core

The ARM[®] Cortex[®]-M0 is a generation of ARM 32-bit RISC processors for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM[®] Cortex[®]-M0 processors feature exceptional code-efficiency, delivering the high performance expected from an ARM core, with memory sizes usually associated with 8- and 16-bit devices.

The STM32F091xB/xC devices embed ARM core and are compatible with all ARM tools and software.

3.2 Memories

The device has the following features:

- 32 Kbytes of embedded SRAM accessed (read/write) at CPU clock speed with 0 wait states and featuring embedded parity checking with exception generation for fail-critical applications.
- The non-volatile memory is divided into two arrays:
 - up to 256 Kbytes of embedded Flash memory for programs and data
 - Option bytes

The option bytes are used to write-protect the memory (with 4 KB granularity) and/or readout-protect the whole memory with the following options:

- Level 0: no readout protection
- Level 1: memory readout protection, the Flash memory cannot be read from or written to if either debug features are connected or boot in RAM is selected
- Level 2: chip readout protection, debug features (Cortex[®]-M0 serial wire) and boot in RAM selection disabled

3.3 Boot modes

At startup, the boot pin and boot selector option bits are used to select one of the three boot options:

- boot from User Flash memory
- boot from System Memory
- boot from embedded SRAM

The boot pin is shared with the standard GPIO and can be disabled through the boot selector option bits. The boot loader is located in System Memory. It is used to reprogram the Flash memory by using USART on pins PA14/PA15 or PA9/PA10 or I²C on pins PB6/PB7.

Additionally, also the internal RC 48 MHz oscillator can be selected for system clock or PLL input source. This oscillator can be automatically fine-trimmed by the means of the CRS peripheral using the external synchronization.

3.7 General-purpose inputs/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions.

The I/O configuration can be locked if needed following a specific sequence in order to avoid spurious writing to the I/Os registers.

3.8 Direct memory access controller (DMA)

The 12-channel general-purpose DMAs (seven channels for DMA1 and five channels for DMA2) manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers.

The DMAs support circular buffer management, removing the need for user code intervention when the controller reaches the end of the buffer.

Each channel is connected to dedicated hardware DMA requests, with support for software trigger on each channel. Configuration is made by software and transfer sizes between source and destination are independent.

DMA can be used with the main peripherals: SPIx, I2Sx, I2Cx, USARTx, all TIMx timers (except TIM14), DAC and ADC.

3.9 Interrupts and events

3.9.1 Nested vectored interrupt controller (NVIC)

The STM32F0xx family embeds a nested vectored interrupt controller able to handle up to 32 maskable interrupt channels (not including the 16 interrupt lines of Cortex[®]-M0) and 4 priority levels.

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of late arriving higher priority interrupts
- Support for tail-chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimal interrupt latency.

Table 13. STM32F091xB/xC pin definitions (continued)

Pin numbers						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	UFBGA64	LQFP64	WLCSP64	LQFP48/UFP48					Alternate functions	Additional functions
C5	91	C4	57	C5	41	PB5	I/O	FT		SPI1_MOSI, I2S1_SD, I2C1_SMBA, TIM16_BKIN, TIM3_CH2, USART5_CK_RTS	WKUP6
B5	92	D3	58	A5	42	PB6	I/O	FTf		I2C1_SCL, USART1_TX, TIM16_CH1N, TSC_G5_I03	-
B4	93	C3	59	B5	43	PB7	I/O	FTf		I2C1_SDA, USART1_RX, USART4_CTS, TIM17_CH1N, TSC_G5_I04	-
A4	94	B4	60	C6	44	PF11-BOOT0	I/O	FT		-	Boot memory selection
A3	95	B3	61	A6	45	PB8	I/O	FTf		I2C1_SCL, CEC, TIM16_CH1, TSC_SYNC, CAN_RX	-
B3	96	A3	62	B6	46	PB9	I/O	FTf		SPI2_NSS, I2S2_WS, I2C1_SDA, IR_OUT, TIM17_CH1, EVENTOUT, CAN_TX	-
C3	97	-	-	-	-	PE0	I/O	FT		EVENTOUT, TIM16_CH1	-
A2	98	-	-	-	-	PE1	I/O	FT		EVENTOUT, TIM17_CH1	-
D3	99	D4	63	A7	47	VSS	S	-		Ground	
C4	100	E4	64	A8	48	VDD	S	-		Digital power supply	

- PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited:
 - The speed should not exceed 2 MHz with a maximum load of 30 pF.
 - These GPIOs must not be used as current sources (e.g. to drive an LED).
- After the first RTC domain power-up, PC13, PC14 and PC15 operate as GPIOs. Their function then depends on the content of the RTC registers which are not reset by the system reset. For details on how to manage these GPIOs, refer to the RTC domain and RTC register descriptions in the reference manual.
- PC6, PC7, PC8, PC9, PA8, PA9, PA10, PA11, PA12, PA13, PF6, PA14, PA15, PC10, PC11, PC12, PD0, PD1 and PD2 I/Os are supplied by VDDIO2
- After reset, these pins are configured as SWDIO and SWCLK alternate functions, and the internal pull-up on the SWDIO pin and the internal pull-down on the SWCLK pin are activated.

Table 14. Alternate functions selected through GPIOA_AFR registers for port A

Pin name	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
PA0	-	USART2_CTS	TIM2_CH1_ETR	TSC_G1_IO1	USART4_TX	-	-	COMP1_OUT
PA1	EVENTOUT	USART2_RTS	TIM2_CH2	TSC_G1_IO2	USART4_RX	TIM15_CH1N	-	-
PA2	TIM15_CH1	USART2_TX	TIM2_CH3	TSC_G1_IO3	-	-	-	COMP2_OUT
PA3	TIM15_CH2	USART2_RX	TIM2_CH4	TSC_G1_IO4	-	-	-	-
PA4	SPI1_NSS, I2S1_WS	USART2_CK	-	TSC_G2_IO1	TIM14_CH1	USART6_TX	-	-
PA5	SPI1_SCK, I2S1_CK	CEC	TIM2_CH1_ETR	TSC_G2_IO2	-	USART6_RX	-	-
PA6	SPI1_MISO, I2S1_MCK	TIM3_CH1	TIM1_BKIN	TSC_G2_IO3	USART3_CTS	TIM16_CH1	EVENTOUT	COMP1_OUT
PA7	SPI1_MOSI, I2S1_SD	TIM3_CH2	TIM1_CH1N	TSC_G2_IO4	TIM14_CH1	TIM17_CH1	EVENTOUT	COMP2_OUT
PA8	MCO	USART1_CK	TIM1_CH1	EVENTOUT	CRS_SYNC	-	-	-
PA9	TIM15_BKIN	USART1_TX	TIM1_CH2	TSC_G4_IO1	I2C1_SCL	MCO	-	-
PA10	TIM17_BKIN	USART1_RX	TIM1_CH3	TSC_G4_IO2	I2C1_SDA	-	-	-
PA11	EVENTOUT	USART1_CTS	TIM1_CH4	TSC_G4_IO3	CAN_RX	I2C2_SCL	-	COMP1_OUT
PA12	EVENTOUT	USART1_RTS	TIM1_ETR	TSC_G4_IO4	CAN_TX	I2C2_SDA	-	COMP2_OUT
PA13	SWDIO	IR_OUT	-	-	-	-	-	-
PA14	SWCLK	USART2_TX	-	-	-	-	-	-
PA15	SPI1_NSS, I2S1_WS	USART2_RX	TIM2_CH1_ETR	EVENTOUT	USART4_RTS	-	-	-



Table 15. Alternate functions selected through GPIOB_AFR registers for port B

Pin name	AF0	AF1	AF2	AF3	AF4	AF5
PB0	EVENTOUT	TIM3_CH3	TIM1_CH2N	TSC_G3_IO2	USART3_CK	-
PB1	TIM14_CH1	TIM3_CH4	TIM1_CH3N	TSC_G3_IO3	USART3_RTS	-
PB2	-	-	-	TSC_G3_IO4	-	-
PB3	SPI1_SCK, I2S1_CK	EVENTOUT	TIM2_CH2	TSC_G5_IO1	USART5_TX	-
PB4	SPI1_MISO, I2S1_MCK	TIM3_CH1	EVENTOUT	TSC_G5_IO2	USART5_RX	TIM17_BKIN
PB5	SPI1_MOSI, I2S1_SD	TIM3_CH2	TIM16_BKIN	I2C1_SMBA	USART5_CK_RTS	-
PB6	USART1_TX	I2C1_SCL	TIM16_CH1N	TSC_G5_IO3	-	-
PB7	USART1_RX	I2C1_SDA	TIM17_CH1N	TSC_G5_IO4	USART4_CTS	-
PB8	CEC	I2C1_SCL	TIM16_CH1	TSC_SYNC	CAN_RX	-
PB9	IR_OUT	I2C1_SDA	TIM17_CH1	EVENTOUT	CAN_TX	SPI2_NSS, I2S2_WS
PB10	CEC	I2C2_SCL	TIM2_CH3	TSC_SYNC	USART3_TX	SPI2_SCK, I2S2_CK
PB11	EVENTOUT	I2C2_SDA	TIM2_CH4	TSC_G6_IO1	USART3_RX	-
PB12	SPI2_NSS, I2S2_WS	EVENTOUT	TIM1_BKIN	TSC_G6_IO2	USART3_CK	TIM15_BKIN
PB13	SPI2_SCK, I2S2_CK	-	TIM1_CH1N	TSC_G6_IO3	USART3_CTS	I2C2_SCL
PB14	SPI2_MISO, I2S2_MCK	TIM15_CH1	TIM1_CH2N	TSC_G6_IO4	USART3_RTS	I2C2_SDA
PB15	SPI2_MOSI, I2S2_SD	TIM15_CH2	TIM1_CH3N	TIM15_CH1N	-	-

Table 18. Alternate functions selected through GPIOE_AFR registers for port E

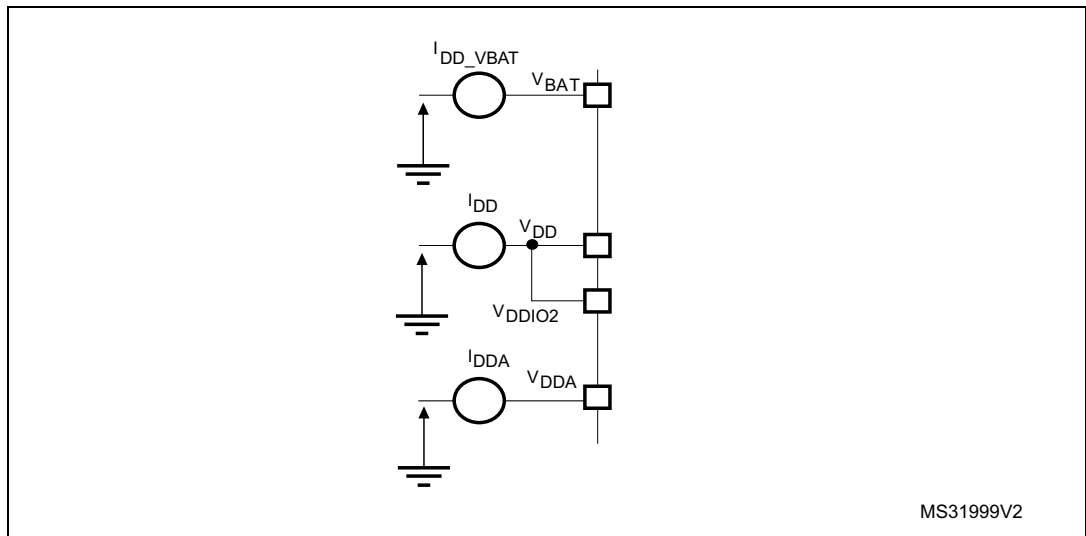
Pin name	AF0	AF1
PE0	TIM16_CH1	EVENTOUT
PE1	TIM17_CH1	EVENTOUT
PE2	TIM3_ETR	TSC_G7_IO1
PE3	TIM3_CH1	TSC_G7_IO2
PE4	TIM3_CH2	TSC_G7_IO3
PE5	TIM3_CH3	TSC_G7_IO4
PE6	TIM3_CH4	-
PE7	TIM1_ETR	USART5_CK_RTS
PE8	TIM1_CH1N	USART4_TX
PE9	TIM1_CH1	USART4_RX
PE10	TIM1_CH2N	USART5_TX
PE11	TIM1_CH2	USART5_RX
PE12	TIM1_CH3N	SPI1_NSS, I2S1_WS
PE13	TIM1_CH3	SPI1_SCK, I2S1_CK
PE14	TIM1_CH4	SPI1_MISO, I2S1_MCK
PE15	TIM1_BKIN	SPI1_MOSI, I2S1_SD

Table 19. Alternate functions selected through GPIOF_AFR registers for port F

Pin name	AF0	AF1	AF2
PF0	CRS_SYNC	I2C1_SDA	-
PF1	-	I2C1_SCL	-
PF2	EVENTOUT	USART7_TX	USART7_CK_RTS
PF3	EVENTOUT	USART7_RX	USART6_CK_RTS
PF6	-	-	-
PF9	TIM15_CH1	USART6_TX	-
PF10	TIM15_CH2	USART6_RX	-

6.1.7 Current consumption measurement

Figure 14. Current consumption measurement scheme



Typical and maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in analog input mode
- All peripherals are disabled except when explicitly mentioned
- The Flash memory access time is adjusted to the f_{HCLK} frequency:
 - 0 wait state and Prefetch OFF from 0 to 24 MHz
 - 1 wait state and Prefetch ON above 24 MHz
- When the peripherals are enabled $f_{PCLK} = f_{HCLK}$

The parameters given in [Table 29](#) to [Table 32](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 24: General operating conditions](#).

1. Data based on characterization results, not tested in production unless otherwise specified.

Table 30. Typical and maximum current consumption from the V_{DDA} supply

Symbol	Para-meter	Conditions (1)	f _{HCLK}	V _{DDA} = 2.4 V				V _{DDA} = 3.6 V				Unit
				Typ	Max @ T _A ⁽²⁾			Typ	Max @ T _A ⁽²⁾			
					25 °C	85 °C	105 °C		25 °C	85 °C	105 °C	
I _{DDA}	Supply current in Run or Sleep mode, code executing from Flash memory or RAM	HSI48	48 MHz	312	333	338	347	316	334	341	350	μA
		HSE bypass, PLL on	48 MHz	147	168	178	181	160	181	192	197	
			32 MHz	101	119	125	127	109	127	135	138	
			24 MHz	80	96	98	100	87	101	106	109	
		HSE bypass, PLL off	8 MHz	2.8	3.5	3.7	3.9	3.7	4.3	4.6	4.7	
			1 MHz	2.7	3.2	3.5	3.8	3.3	3.9	4.4	4.7	
		HSI clock, PLL on	48 MHz	214	243	254	259	235	262	275	281	
			32 MHz	166	193	203	204	185	207	216	220	
			24 MHz	144	171	177	178	161	180	187	190	
		HSI clock, PLL off	8 MHz	65	83	85	86	77	90	92	93	

1. Current consumption from the V_{DDA} supply is independent of whether the digital peripherals are enabled or disabled, being in Run or Sleep mode or executing from Flash memory or RAM. Furthermore, when the PLL is off, I_{DDA} is independent from the frequency.

2. Data based on characterization results, not tested in production unless otherwise specified.

Table 31. Typical and maximum consumption in Stop and Standby modes

Sym- bol	Para- meter	Conditions	Typ @V _{DD} (V _{DD} = V _{DDA})						Max ⁽¹⁾			Unit
			2.0 V	2.4 V	2.7 V	3.0 V	3.3 V	3.6 V	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	
I _{DD}	Supply current in Stop mode	Regulator in run mode, all oscillators OFF	14.6	14.8	14.9	15.1	15.4	15.8	18	51	97	μA
		Regulator in low-power mode, all oscillators OFF	3.3	3.4	3.6	3.8	4.1	4.4	11	53	106	
	Supply current in Standby mode	LSI ON and IWDG ON	0.9	1.0	1.1	1.2	1.3	1.4	2.3	2.7	3.6	
		LSI OFF and IWDG OFF	0.6	0.7	0.8	0.9	1.0	1.1	1.9	2.3	3.0	
I _{DDA}	Supply current in Stop mode	V _{DDA} monitoring ON	Regulator in run mode, all oscillators OFF	1.9	2.0	2.2	2.3	2.4	2.6	3.8	4.2	4.6
			Regulator in low-power mode, all oscillators OFF	1.9	2.0	2.2	2.3	2.4	2.6	3.8	4.2	4.6
	Supply current in Standby mode	V _{DDA} monitoring ON	LSI ON and IWDG ON	2.3	2.5	2.7	2.8	3.0	3.3	3.8	4.2	4.8
			LSI OFF and IWDG OFF	1.8	1.9	2.0	2.2	2.3	2.5	3.6	3.9	4.2
	Supply current in Stop mode	V _{DDA} monitoring OFF	Regulator in run mode, all oscillators OFF	1.2	1.2	1.3	1.3	1.4	1.4	-	-	-
			Regulator in low-power mode, all oscillators OFF	1.2	1.2	1.3	1.3	1.4	1.4	-	-	-
	Supply current in Standby mode	V _{DDA} monitoring OFF	LSI ON and IWDG ON	1.6	1.7	1.8	1.9	2.0	2.1	-	-	-
			LSI OFF and IWDG OFF	1.1	1.1	1.1	1.2	1.3	1.3	-	-	-

1. Data based on characterization results, not tested in production unless otherwise specified.

Table 35. Peripheral current consumption (continued)

Peripheral		Typical consumption at 25 °C	Unit
APB	APB-Bridge ⁽²⁾	3.6	μA/MHz
	ADC ⁽³⁾	4.3	
	CAN	12.4	
	CEC	0.4	
	CRS	0.0	
	DAC ⁽³⁾	4.2	
	DBG (MCU Debug Support)	0.2	
	I2C1	2.9	
	I2C2	2.4	
	PWR	0.6	
	SPI1	8.8	
	SPI2	7.8	
	SYSCFG and COMP	1.9	
	TIM1	15.2	
	TIM14	2.6	
	TIM15	8.7	
	TIM16	5.8	
	TIM17	7.0	
	TIM2	16.2	
	TIM3	11.9	
	TIM6	11.8	
	TIM7	2.5	
	USART1	17.6	
	USART2	16.3	
	USART3	16.2	
	USART4	4.7	
	USART5	4.4	
	USART6	5.5	
	USART7	5.2	
	USART8	5.1	
	WWDG	1.1	
	All APB peripherals	207.2	

1. The BusMatrix is automatically active when at least one master is ON (CPU, DMA).
2. The APB Bridge is automatically active when at least one peripheral is ON on the Bus.
3. The power consumption of the analog part (I_{DDA}) of peripherals such as ADC, DAC, comparators, is not included. Refer to the tables of characteristics in the subsequent sections.

Table 47. Flash memory endurance and data retention

Symbol	Parameter	Conditions	Min ⁽¹⁾	Unit
N _{END}	Endurance	T _A = -40 to +105 °C	10	kcycle
t _{RET}	Data retention	1 kcycle ⁽²⁾ at T _A = 85 °C	30	Year
		1 kcycle ⁽²⁾ at T _A = 105 °C	10	
		10 kcycle ⁽²⁾ at T _A = 55 °C	20	

1. Data based on characterization results, not tested in production.

2. Cycling performed over the whole temperature range.

6.3.11 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

Functional EMS (electromagnetic susceptibility)

While a simple application is executed on the device (toggling 2 LEDs through I/O ports), the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- **Electrostatic discharge (ESD)** (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- **FTB:** A Burst of Fast Transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in [Table 48](#). They are based on the EMS levels and classes defined in application note AN1709.

Table 48. EMS characteristics

Symbol	Parameter	Conditions	Level/Class
V _{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V _{DD} = 3.3 V, LQFP100, T _A = +25 °C, f _{HCLK} = 48 MHz, conforming to IEC 61000-4-2	2B
V _{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V _{DD} and V _{SS} pins to induce a functional disturbance	V _{DD} = 3.3 V, LQFP100, T _A = +25 °C, f _{HCLK} = 48 MHz, conforming to IEC 61000-4-4	4B

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

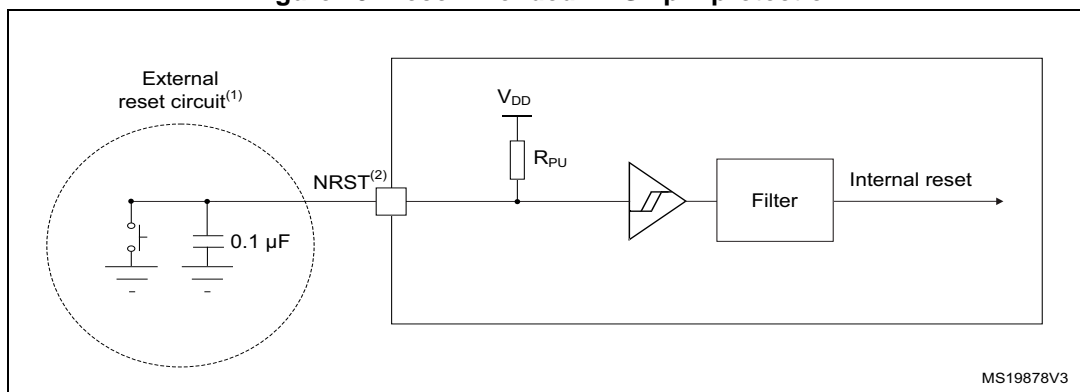
Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Table 56. NRST pin characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{\text{hys(NRST)}}$	NRST Schmitt trigger voltage hysteresis	-	-	200	-	mV
R_{PU}	Weak pull-up equivalent resistor ⁽²⁾	$V_{\text{IN}} = V_{\text{SS}}$	25	40	55	k Ω
$V_{\text{F(NRST)}}$	NRST input filtered pulse	-	-	-	100 ⁽¹⁾	ns
$V_{\text{NF(NRST)}}$	NRST input not filtered pulse	$2.7 < V_{\text{DD}} < 3.6$	300 ⁽³⁾	-	-	ns
		$2.0 < V_{\text{DD}} < 3.6$	500 ⁽³⁾	-	-	

1. Data based on design simulation only. Not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimal (~10% order).
3. Data based on design simulation only. Not tested in production.

Figure 25. Recommended NRST pin protection



1. The external capacitor protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{\text{IL(NRST)}}$ max level specified in [Table 56: NRST pin characteristics](#). Otherwise the reset will not be taken into account by the device.

6.3.16 12-bit ADC characteristics

Unless otherwise specified, the parameters given in [Table 57](#) are derived from tests performed under the conditions summarized in [Table 24: General operating conditions](#).

Note: *It is recommended to perform a calibration after each power-up.*

Table 57. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	2.4	-	3.6	V
$I_{\text{DDA (ADC)}}$	Current consumption of the ADC ⁽¹⁾	$V_{\text{DDA}} = 3.3 \text{ V}$	-	0.9	-	mA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
$f_{\text{S}}^{(2)}$	Sampling rate	12-bit resolution	0.043	-	1	MHz

Table 61. Comparator characteristics (continued)

Symbol	Parameter	Conditions		Min ⁽¹⁾	Typ	Max ⁽¹⁾	Unit
V_{hys}	Comparator hysteresis	No hysteresis (COMPxHYST[1:0]=00)	-	-	0	-	mV
		Low hysteresis (COMPxHYST[1:0]=01)	High speed mode	3	8	13	
			All other power modes	5		10	
		Medium hysteresis (COMPxHYST[1:0]=10)	High speed mode	7	15	26	
			All other power modes	9		19	
		High hysteresis (COMPxHYST[1:0]=11)	High speed mode	18	31	49	
			All other power modes	19		40	

1. Data based on characterization results, not tested in production.

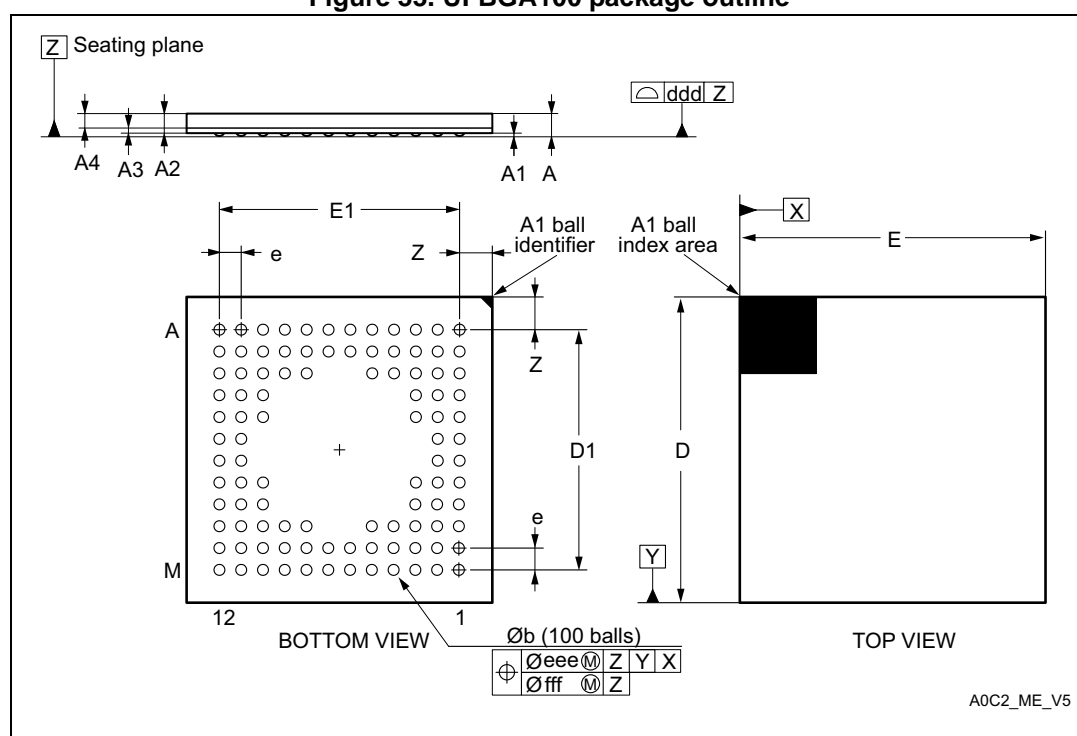
7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

7.1 UFBGA100 package information

UFBGA100 is a 100-ball, 7 x 7 mm, 0.50 mm pitch, ultra-fine-profile ball grid array package.

Figure 33. UFBGA100 package outline



1. Drawing is not to scale.

Table 70. UFBGA100 package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	-	0.600	-	-	0.0236
A1	-	-	0.110	-	-	0.0043
A2	-	0.450	-	-	0.0177	-
A3	-	0.130	-	-	0.0051	0.0094
A4	-	0.320	-	-	0.0126	-

8 Ordering information

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.

Table 81. Ordering information scheme

Example:	STM32	F	091	R	C	T	6	x
Device family STM32 = ARM-based 32-bit microcontroller								
Product type F = General-purpose								
Sub-family 091 = STM32F091xx								
Pin count C = 48 pins R = 64 pins V = 100 pins								
User code memory size B = 128 Kbyte C = 256 Kbyte								
Package H = UFBGA T = LQFP U = UFQFPN Y = WLCSP								
Temperature range 6 = -40 to 85 °C 7 = -40 to 105 °C								
Options xxx = code ID of programmed parts (includes packing type) TR = tape and reel packing blank = tray packing								